

LIST OF PRIOR ART CITED BY APPLICANT (PTO-1449)		ATTY. DOCKET NO. P-0650		APPLN. SERIAL NO. New U.S. Application. 6/815/4			
		APPLICANT(S) Woong-Gil CHOI					
		CUSTOMER NO. 34610					
		FILING DATE April 2, 2004		GROUP art unit 2618			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
OP	5,898,925	04/27/1999	Honkasalo et al.	455	437	5/10/1995	
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No	
OP	11-008587	01/12/1999	JAPAN (Full Japanese Text)	—	—	Abst. only	
OP	2001-186567	07/06/2001	JAPAN (Full Japanese Text)	—	—	Abst. only	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EXAMINER	[Signature]			DATE CONSIDERED 07/06/07			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

[illegible]

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[illegible]

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LIST OF ART CITED BY APPLICANT (PTO-1449)				ATTY. DOCKET NO. P-0650		APPLN. SERIAL NO. 10/815,668	
				APPLICANT(S) Woong-Gil CHOI			
				FILING DATE April 2, 2004		GROUP 2681 2618	

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS					
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

U.S. PATENT APPLICATIONS					
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EP	JP 10-093495	04/19/1998	JAPAN (English Abstract and Japanese Full Text)			X	
EP	JP 5-507592	10/28/1993	JAPAN (English Abstract and Japanese Full Text)			X	
EP	EP 0 624 003 A2	11/09/1994	EUROPE (English Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)	
EP	Chinese Office Action dated April 21, 2006 in corresponding Chinese Patent Application No. 200410034623.7 with English Translation
EP	Japanese Office Action dated May 9, 2006 in corresponding Japanese Patent Application No. 2004-120455 (no English translation available)

EXAMINER	DATE CONSIDERED 07/06/07
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.
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